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Patent and Trademark Office: U.S. DEPARTMENT OF COMMERCE

Substitute for form 1449A/PTO

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(use as many sheets as necessary)

Sheet **1** of **8**

Complete if Known

Application Number	10/600,721
Filing Date	6/20/2003
First Named Inventor	Bickford, Randall L.
Group Art Unit	2121
Examiner Name	Not yet Assigned
Attorney Docket Number	23406-cip

U.S. PATENT DOCUMENTS

Examiner Initials ¹	Cite No. ¹	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code ² (if known)			
Rb	1	4,295,128		Hashemian et al.	10-13-1981	
	2	4,478,783		Broadwater	10-23-1984	
	3	4,761,748		Le Rat et al.	08-02-1988	
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	7	5,223,207		Gross et al.	06-29-1993	
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	9	5,381,140		Kuroda, et al.	01-10-1995	
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	20	5,680,409		Qin et al.	10-21-1997	

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		Office ³	Number ⁴	Kind Code ⁵ (if known)				

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Signature

Ramona Patel

Date
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1/30/05

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¹ Unique citation designation number. ² See attached Kinds of U.S. Patent Documents. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

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	22	5,740,033		Wassick et al.	04-14-1998	
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Signature**

Ramc S Patel

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)		Application Number	10/600,721
		Filing Date	6/20/2003
		First Named Inventor	Bickford, Randall L.
		Group Art Unit	2121
		Examiner Name	Not yet Assigned
		Attorney Docket Number	23406-cip
Sheet	5	of	8

OTHER PRIOR ART – NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
R.P.	62	BICKFORD, R.L., Phase Partitioning the Multivariate State Estimation Technique (MSET) Process for Improved Parameter Estimation Performance and Processing Speed, New Technology Report, January 13, 2000, Printed in USA by Expert Microsystems, Inc.	
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Examiner Signature	<i>Ramesh Patel</i>	Date Considered	1/30/05
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		Filing Date	6/20/2003
		First Named Inventor	Bickford, Randall L.
		Group Art Unit	2121
		Examiner Name	Not yet Assigned
Sheet 6	of 8	Attorney Docket Number	23406-clp

OTHER PRIOR ART – NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
RB	73	BICKFORD, R.L., et al, Real-Time Space Shuttle Main Engine Sensor Validation, National Aeronautics and Space Administration, August 1995, Printed in USA by ExperTech & Intelligent Software Associates, Inc.	
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Examiner Signature	<i>Ramsey Patel</i>	Date Considered	1/30/05
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		First Named Inventor	Bickford, Randall L.		
		Group Art Unit	2121		
		Examiner Name	Not yet Assigned		
Sheet	7	of	8	Attorney Docket Number	23406-cip

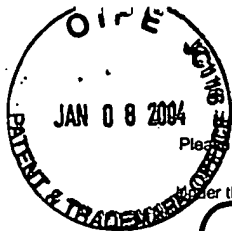
OTHER PRIOR ART – NON PATENT LITERATURE DOCUMENTS			
Examiner Initials [*]	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
RL	84	SINGER, R.M., et al, Use of a Pattern Recognition Scheme to Compensate for Critical Sensor Failures, 1st Intl. Machinery Monitoring and Diagnostic Conf., September 1989, Printed in USA by Argonne National Laboratory	
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Examiner Signature	<i>Randy Patel</i>	Date Considered	1/30/05
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<i>RL</i>	95	WEGERICH, S., et al, Challenges Facing Equipment Condition Monitoring Systems, MARCOM 2001, May 2001, Printed in USA by SmartSignal Corporation	
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Randy Ratz

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